PD - 95416

International
IOR Rectifier

IRFB9N65APbF

SMPS MOSFET

HEXFET® Power MOSFET

V_{DSS}	$R_{DS(on)}$ max	I_D
650V	0.93Ω	8.5A

Applications

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching
- Lead-Free

Benefits

- Low Gate Charge Qg results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dv/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current

TO-220AB

Absolute Maximum Ratings

	Parameter	Max.	Units
I_D @ T_C = 25°C	Continuous Drain Current, V_{GS} @ 10V	8.5	A
I_D @ T_C = 100°C	Continuous Drain Current, V_{GS} @ 10V	5.4	
I_{DM}	Pulsed Drain Current ①⑧	21	
P_D @T_C = 25°C	Power Dissipation	167	W
	Linear Derating Factor	1.3	W/°C
V_{GS}	Gate-to-Source Voltage	± 30	V
dv/dt	Peak Diode Recovery dv/dt ③⑧	2.8	V/ns
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 150	°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torqe, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

Typical SMPS Topologies

- Single Transistor Flyback
- Single Transistor Forward

Notes ① through ⑤ are on page 8

Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	650	—	—	V	V_{GS} = 0V, I_D = 250µA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.67	—	V/°C	Reference to 25°C, I_D = 1mA⑥
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	—	0.93	Ω	V_{GS} = 10V, I_D = 5.1.A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0	—	4.0	V	V_{DS} = V_{GS}, I_D = 250µA
I_{DSS}	Drain-to-Source Leakage Current	—	—	25	µA	V_{DS} = 650V, V_{GS} = 0V
		—	—	250		V_{DS} = 520V, V_{GS} = 0V, T_J = 125°C
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	V_{GS} = 30V
	Gate-to-Source Reverse Leakage	—	—	-100		V_{GS} = -30V

Dynamic @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
g_{fs}	Forward Transconductance	3.9	—	—	S	V_{DS} = 50V, I_D = 3.1A⑧
Q_g	Total Gate Charge	—	—	48	nC	I_D = 5.2A
Q_{gs}	Gate-to-Source Charge	—	—	12		V_{DS} = 400V
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	—	19		V_{GS} = 10V, See Fig. 6 and 13 ④⑧
$t_{d(on)}$	Turn-On Delay Time	—	14	—	ns	V_{DD} = 325V
t_r	Rise Time	—	20	—		I_D = 5.2A
$t_{d(off)}$	Turn-Off Delay Time	—	34	—		R_G = 9.1Ω
t_f	Fall Time	—	18	—		R_D = 62Ω,See Fig. 10 ④⑧
C_{iss}	Input Capacitance	—	1417	—	pF	V_{GS} = 0V
C_{oss}	Output Capacitance	—	177	—		V_{DS} = 25V
C_{rss}	Reverse Transfer Capacitance	—	7.0	—		f = 1.0MHz, See Fig. 5⑧
C_{oss}	Output Capacitance	—	1912	—		V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz
C_{oss}	Output Capacitance	—	48	—		V_{GS} = 0V, V_{DS} = 520V, f = 1.0MHz
C_{oss} eff.	Effective Output Capacitance	—	84	—		V_{GS} = 0V, V_{DS} = 0V to 520V ⑤⑧

Avalanche Characteristics

	Parameter	Typ.	Max.	Units
E_{AS}	Single Pulse Avalanche Energy②	—	325	mJ
I_{AR}	Avalanche Current①	—	5.2	A
E_{AR}	Repetitive Avalanche Energy①	—	16	mJ

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	0.75	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50	—	
$R_{\theta JA}$	Junction-to-Ambient	—	62	

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	5.2	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	21		
V_{SD}	Diode Forward Voltage	—	—	1.5	V	T_J = 25°C, I_S = 5.2A, V_{GS} = 0V ④
t_{rr}	Reverse Recovery Time	—	493	739	ns	T_J = 25°C, I_F = 5.2A
Q_{rr}	Reverse RecoveryCharge	—	2.1	3.2	µC	di/dt = 100A/µs ④⑧
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

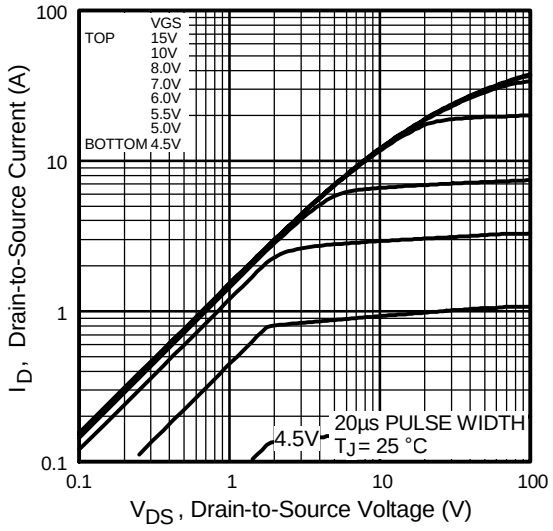


Fig 1. Typical Output Characteristics

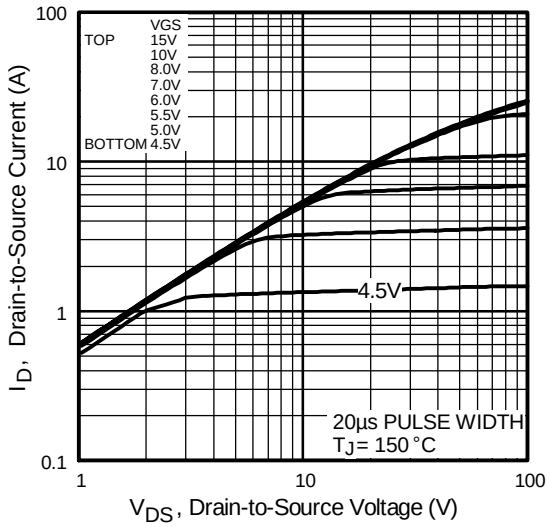


Fig 2. Typical Output Characteristics

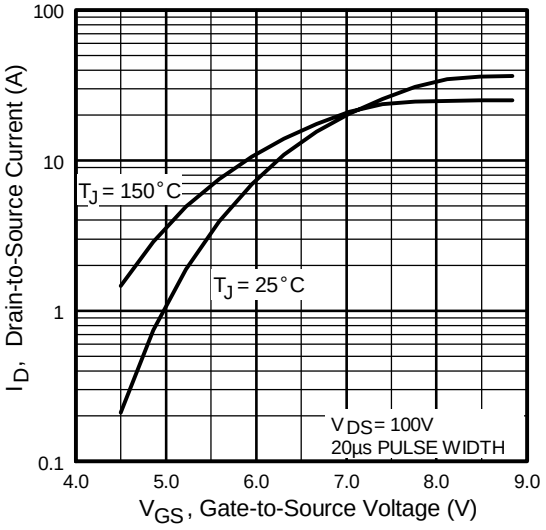


Fig 3. Typical Transfer Characteristics

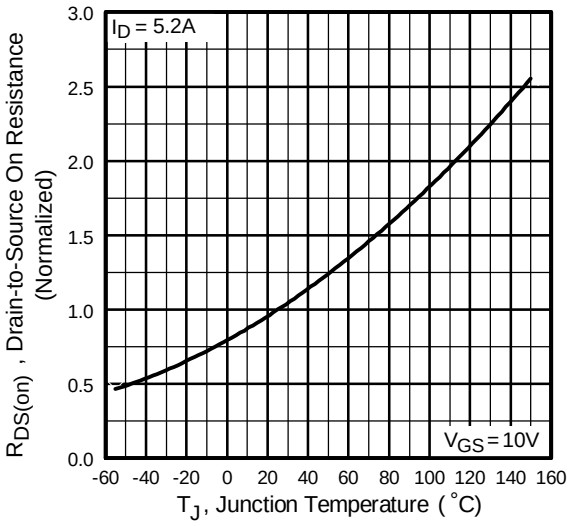


Fig 4. Normalized On-Resistance Vs. Temperature

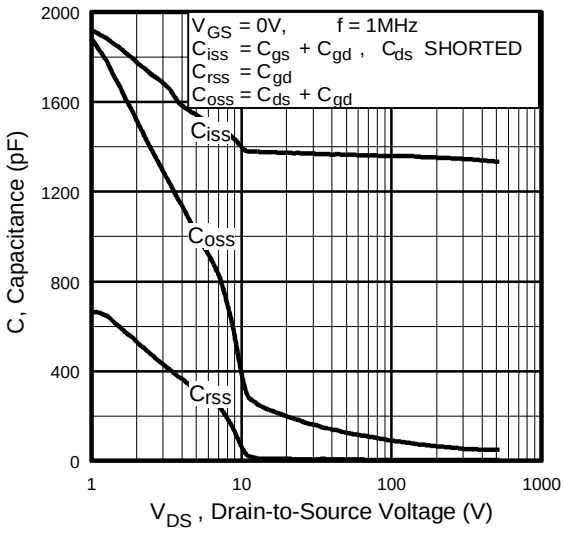


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

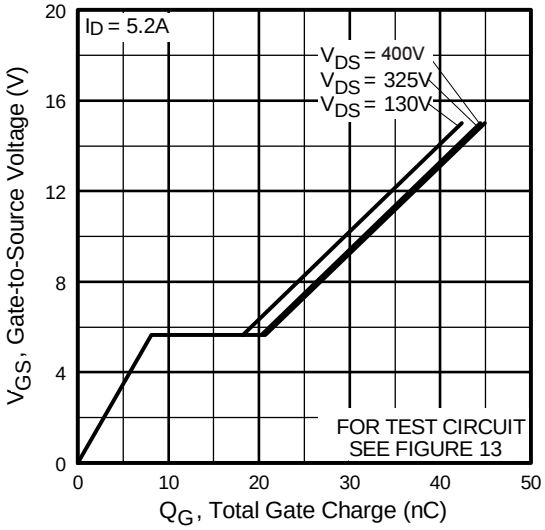


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

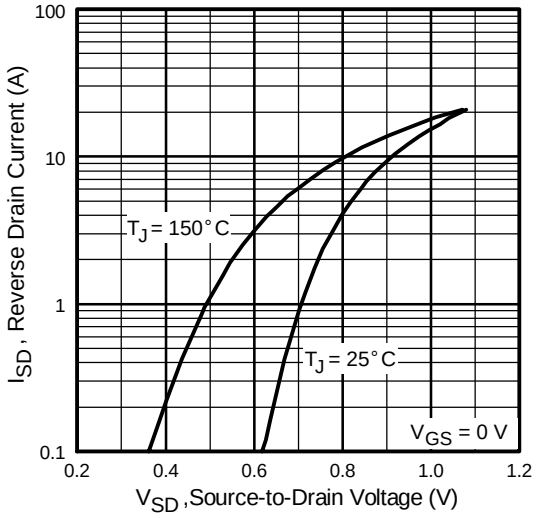


Fig 7. Typical Source-Drain Diode Forward Voltage

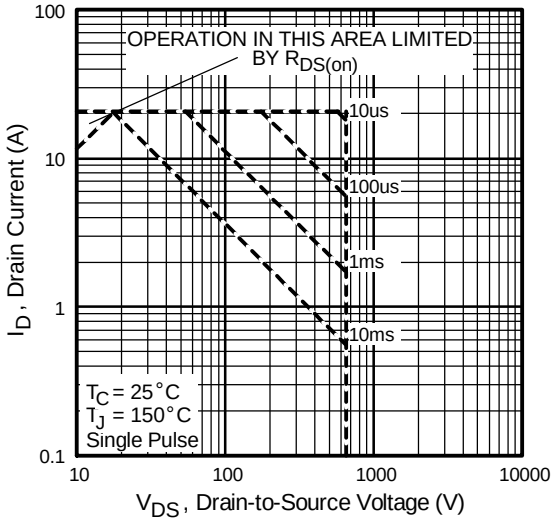


Fig 8. Maximum Safe Operating Area

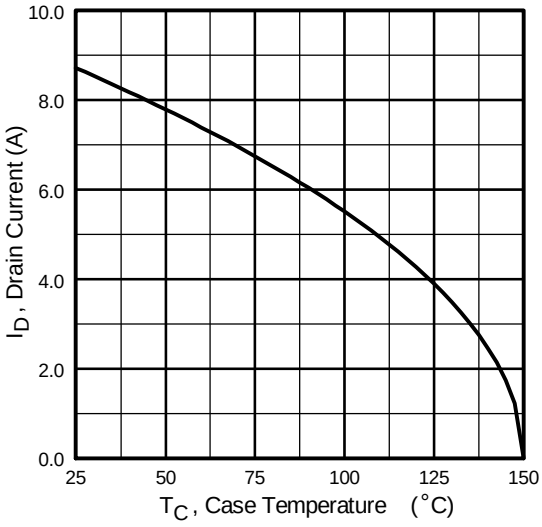


Fig 9. Maximum Drain Current Vs. Case Temperature

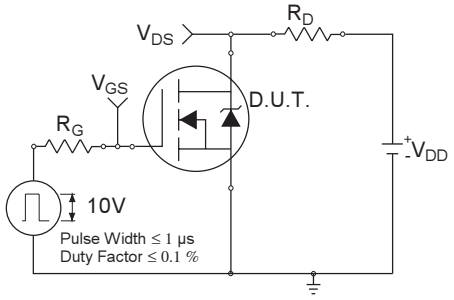


Fig 10a. Switching Time Test Circuit

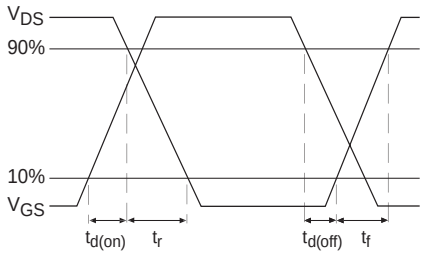


Fig 10b. Switching Time Waveforms

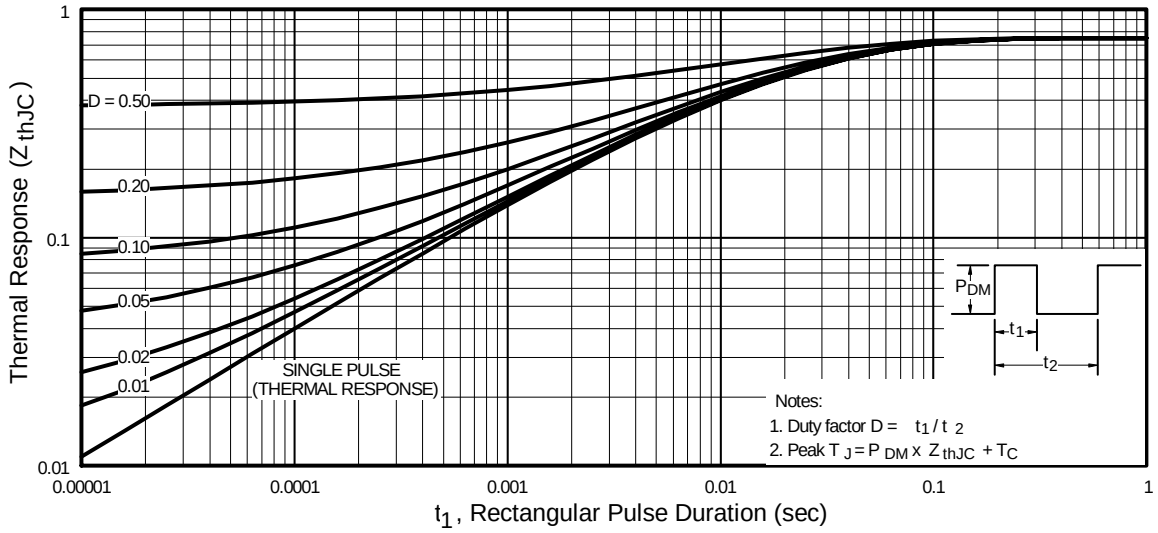


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

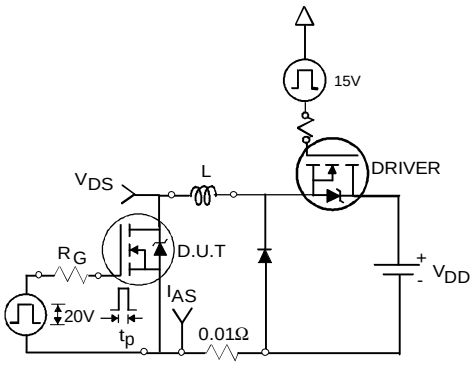


Fig 12a. Unclamped Inductive Test Circuit

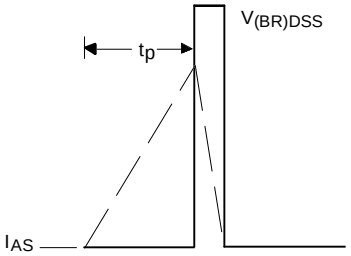


Fig 12b. Unclamped Inductive Waveforms

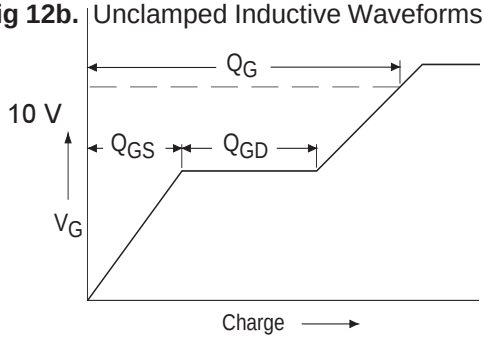


Fig 13a. Basic Gate Charge Waveform

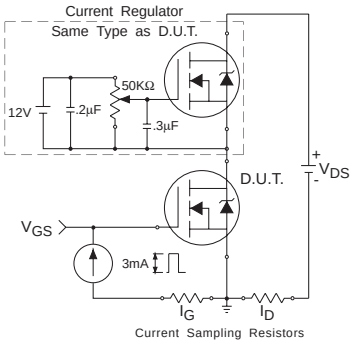


Fig 13b. Gate Charge Test Circuit

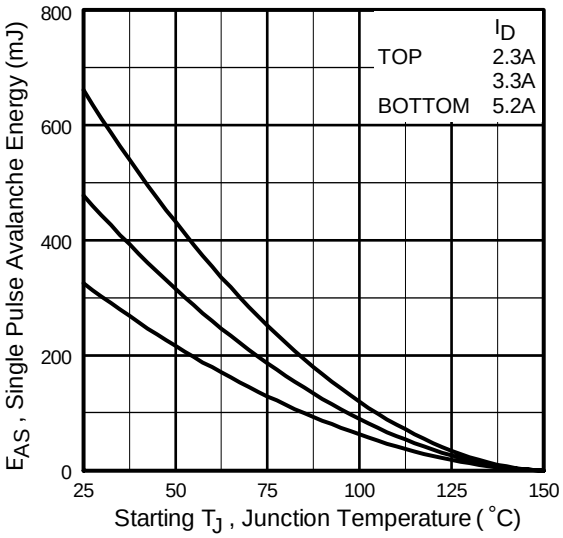


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

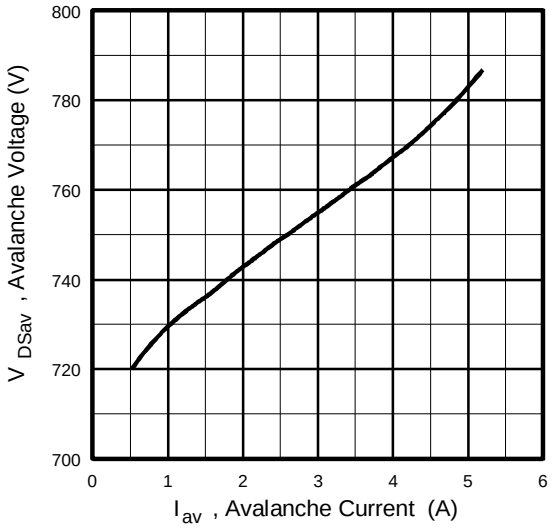


Fig 12d. Typical Drain-to-Source Voltage Vs. Avalanche Current

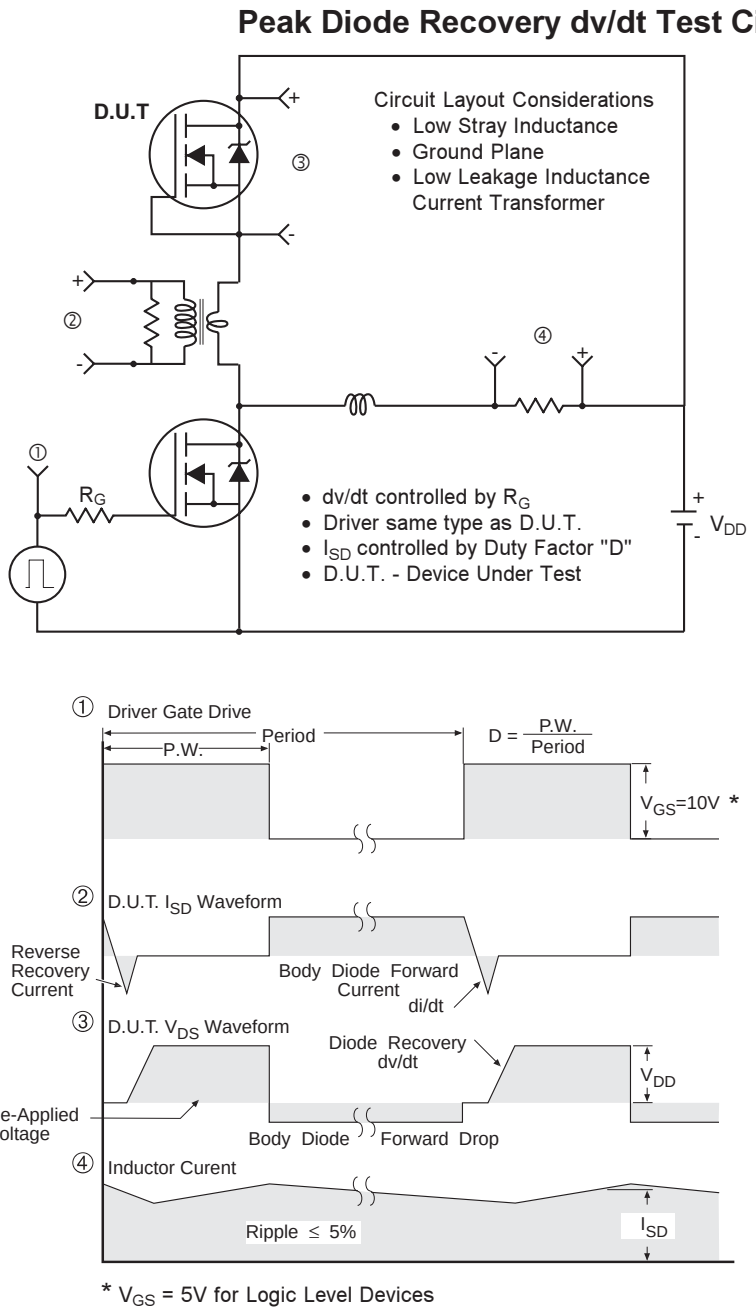
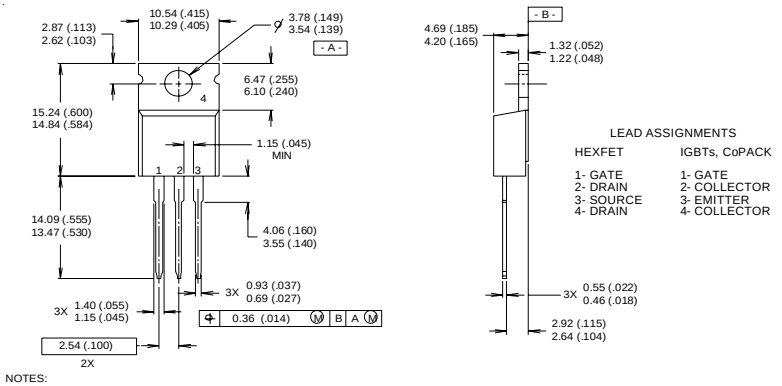


Fig 14. For N-Channel HEXFET® Power MOSFETs

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



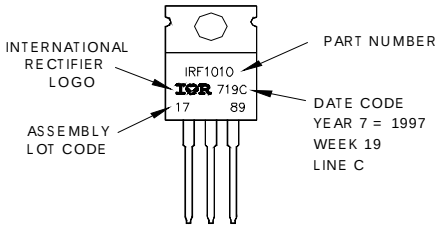
NOTES:

1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
2 CONTROLLING DIMENSION : INCH
3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB.
4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010
LOT CODE 1789
ASSEMBLED ON WW 19, 1997
IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead-Free"



Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

② Starting T_J = 25°C, L = 24mH R_G = 25Ω, I_{AS} = 5.2A. (See Figure 12)

③ $I_{SD} \leq$ 5.2A, di/dt ≤ 90A/µs, $V_{DD} \leq V_{(BR)DSS}$, $T_J \leq$ 150°C

④ Pulse width ≤ 300µs; duty cycle ≤ 2%.

⑤ C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}

⑥ Uses IRFIB5N65A data and test conditions

Data and specifications subject to change without notice.

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